

# A Review of Stress and Strain Effects on Bi-2212

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**LAWRENCE BERKELEY NATIONAL LABORATORY**

# Bi-2212?

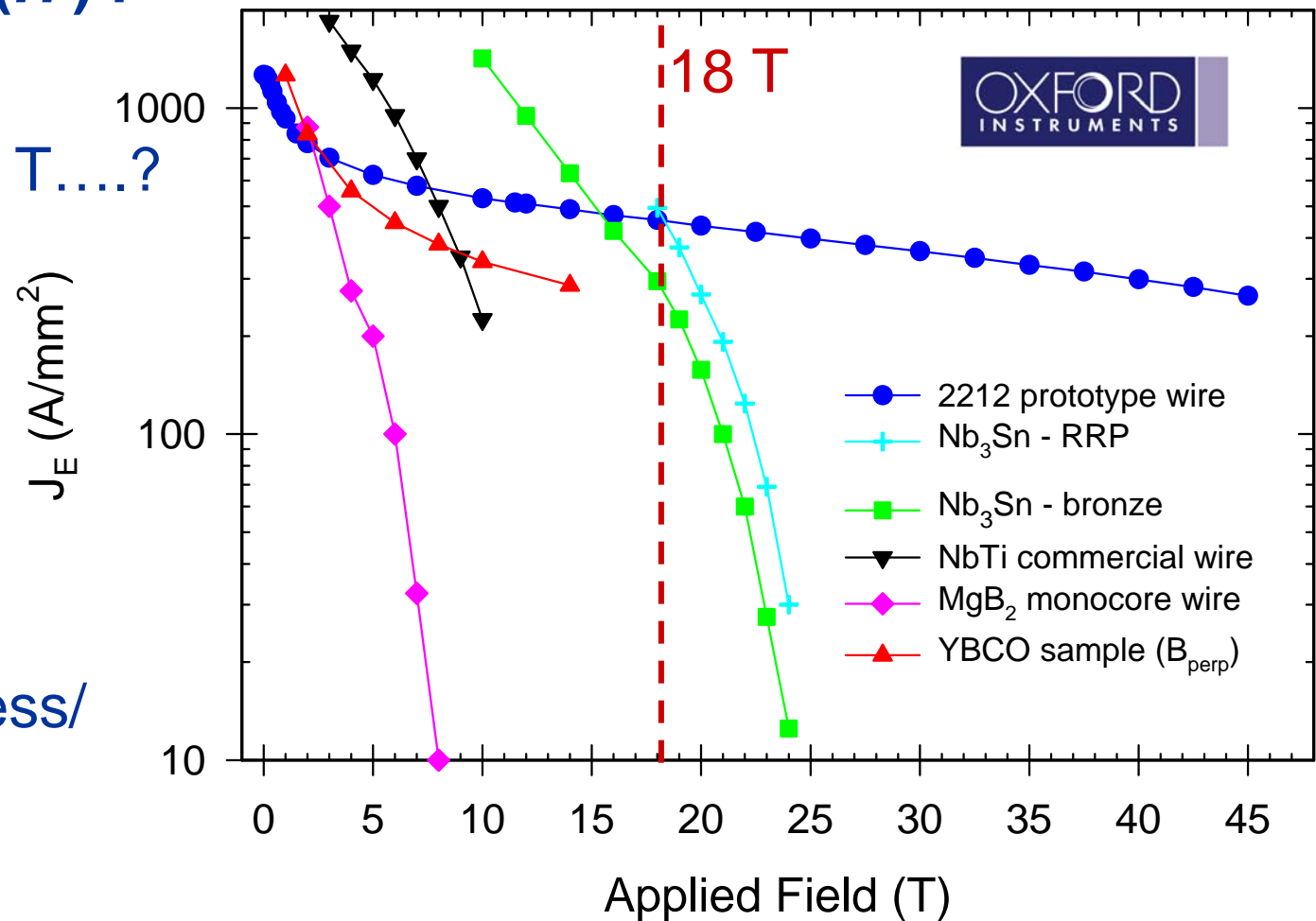


## Engineering $J_E(H)$ !

• 20 T, 30 T, 50 T....?

**But...**

• Bi-2212 is stress/  
strain limited !



• K.R. Marken, MRS spring meeting 2006

# Stress and strain in superconductors

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## Magnet systems

- Thermal contraction differences
- Lorentz loads

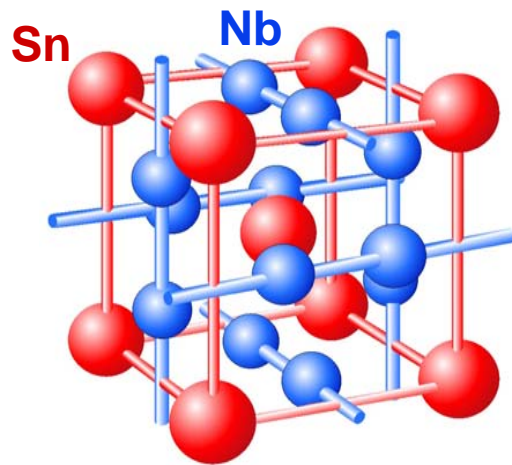
## Short sample tests

- Axial load
- Transverse pressure
- Hydrostatic pressure

# Nb<sub>3</sub>Sn in a nutshell: Axial strain

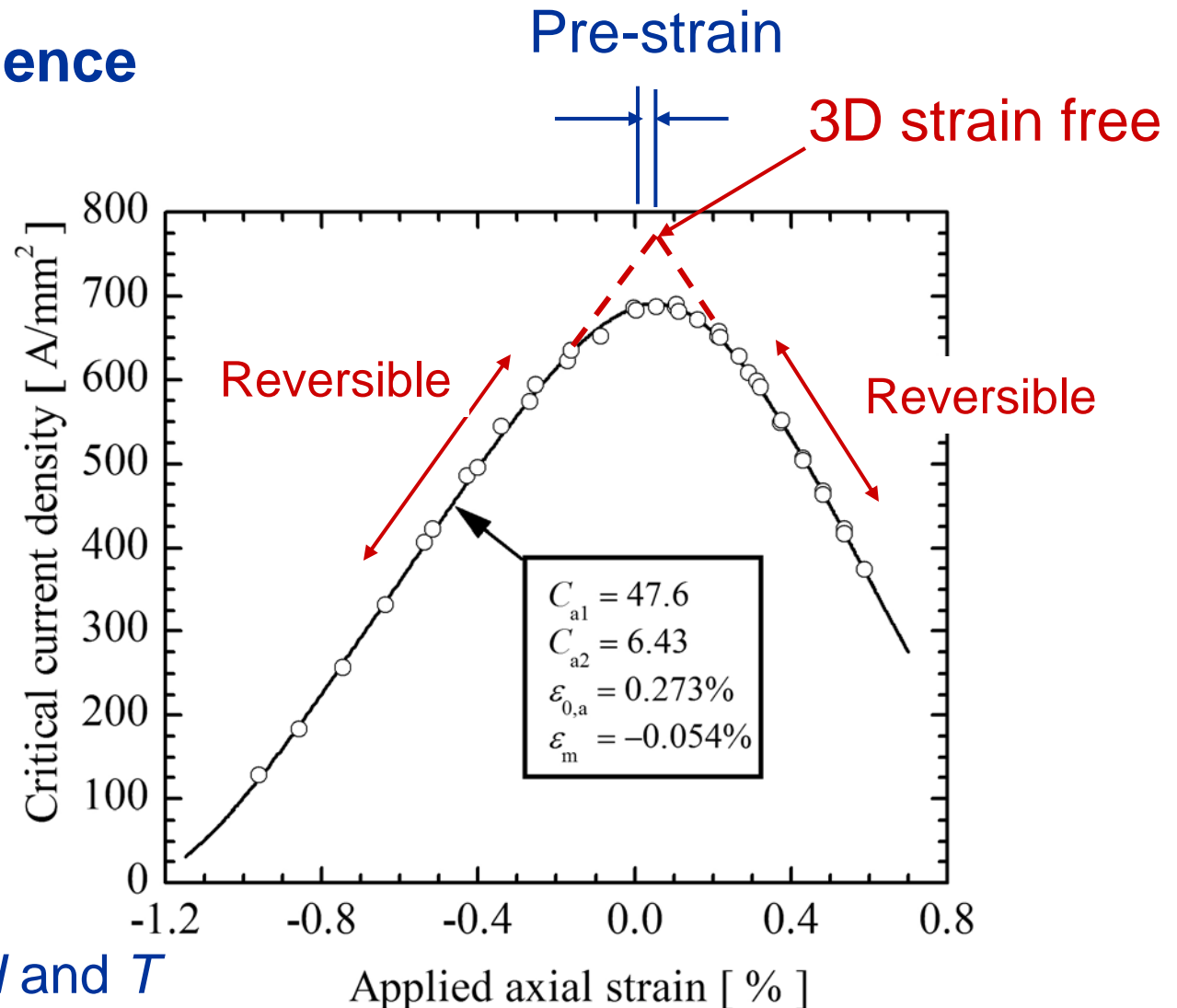


## Axial strain dependence



### Reversible:

- $\Delta \varepsilon \rightarrow \Delta N(E_F), \Delta \lambda_{ep}$
- $\Delta T_c$  and  $\Delta H_{c2}$
- $\Delta J_c$
- Slope depends on  $H$  and  $T$



► Godeke, SuST, 2006

# Nb<sub>3</sub>Sn in a nutshell: Crack formation



## ‘Preliminary’ $J_c$ collapse

- Irreversible
- Crack formation
- ➔ Two (*unrelated*) ITER IT wires

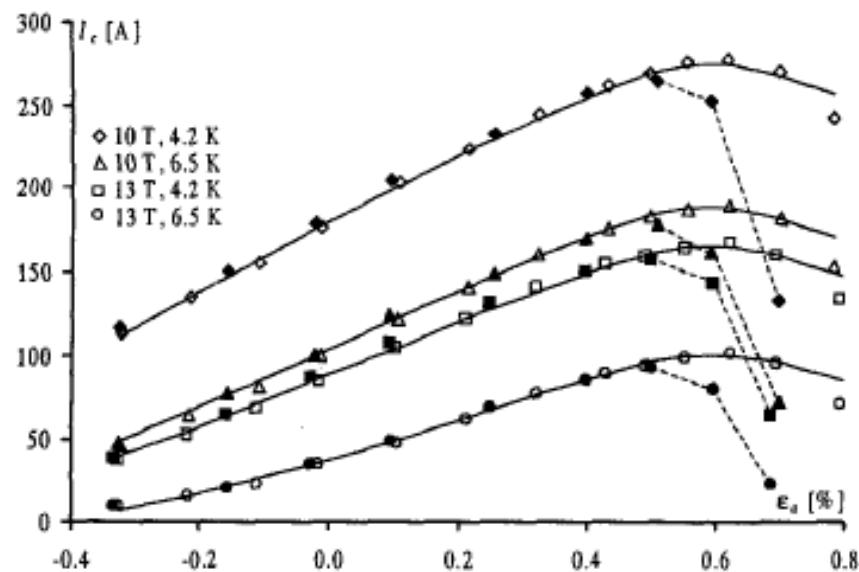
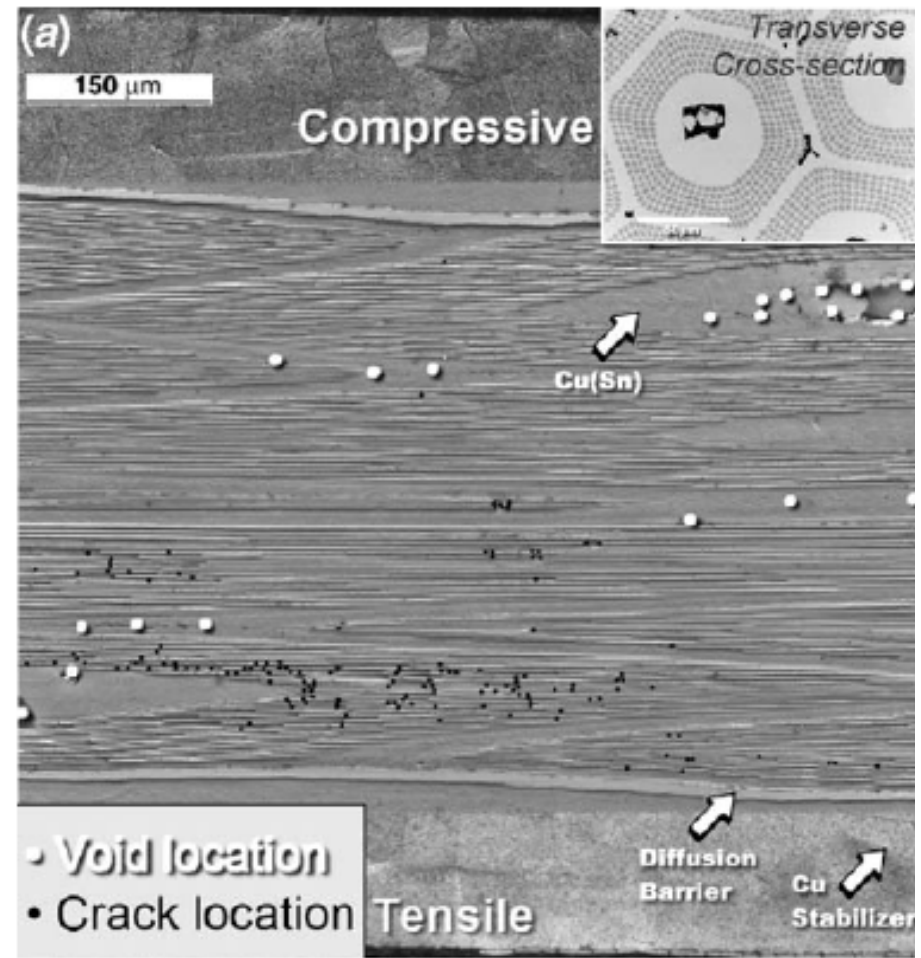


Figure 4: The deformation measurements for conductors B1 and B2 (open and filled markers). The points are measured and the solid lines are calculated with (8), with parameters as listed in Table 2 and Table 3. The dashed lines indicated the deviation from (8).

➔ Godeke, TAS, 1999



➔ Jewell, SuST, 2003

# Nb<sub>3</sub>Sn in a nutshell: Transverse pressure



## On short tape samples

- Worrying ?

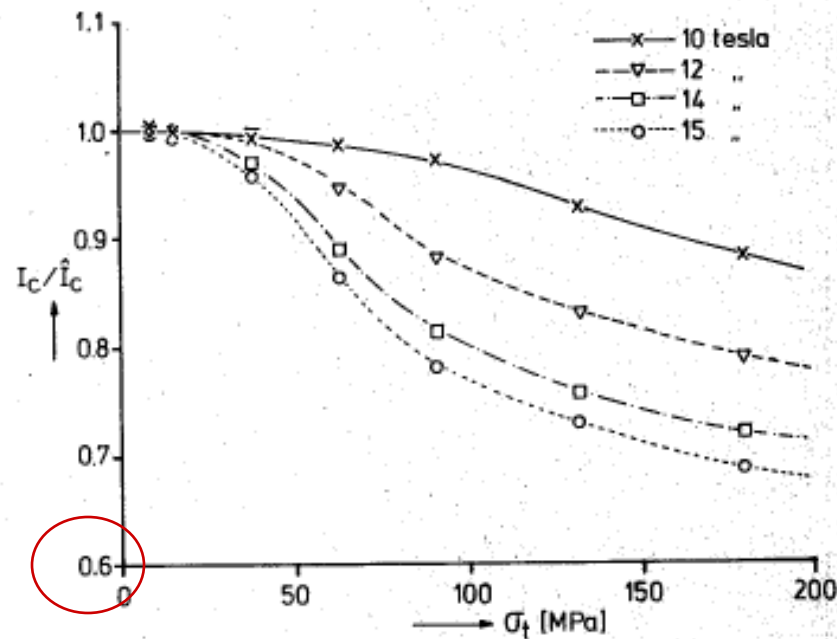


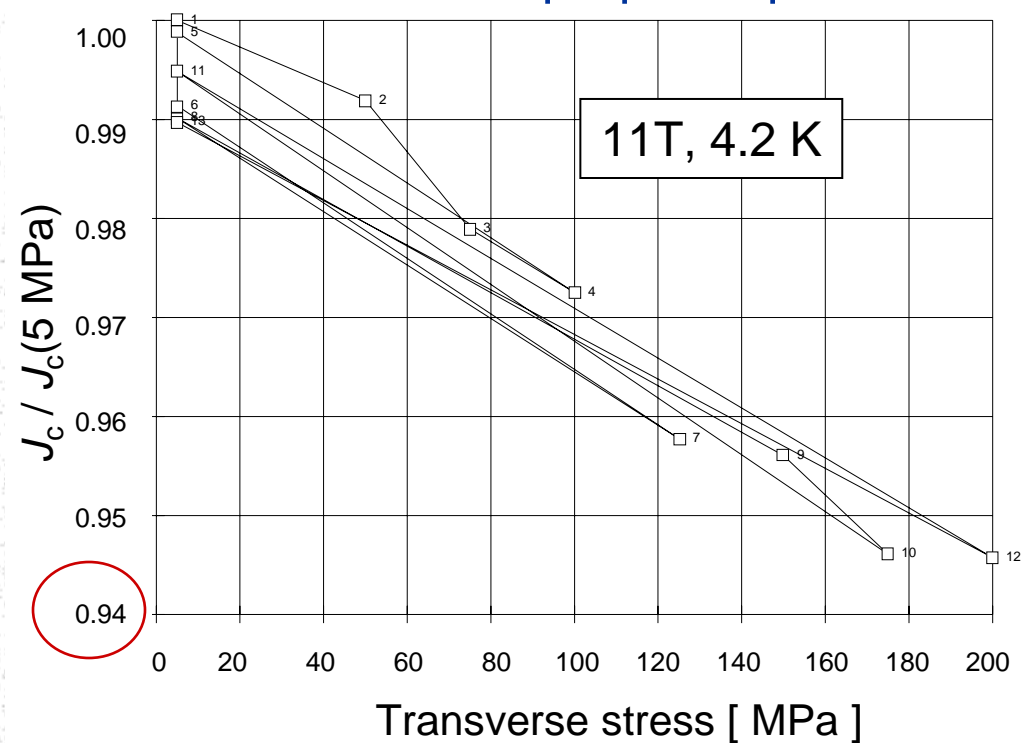
Fig. 4 The relative current density as a function of the transverse pressure at 4.2 K.

► Ten Haken, TAS, 1993

## On cables

- OK !

► Sensitive to proper experiment



► Godeke, Report, 1993

# Bi-2212 – Typical axial tensile behavior



## Strain dependence

- Independent of  $H$  and  $T$
- Always irreversible
  - ➔ Crack formation
- $J_c$  collapse point depends on pre-strain

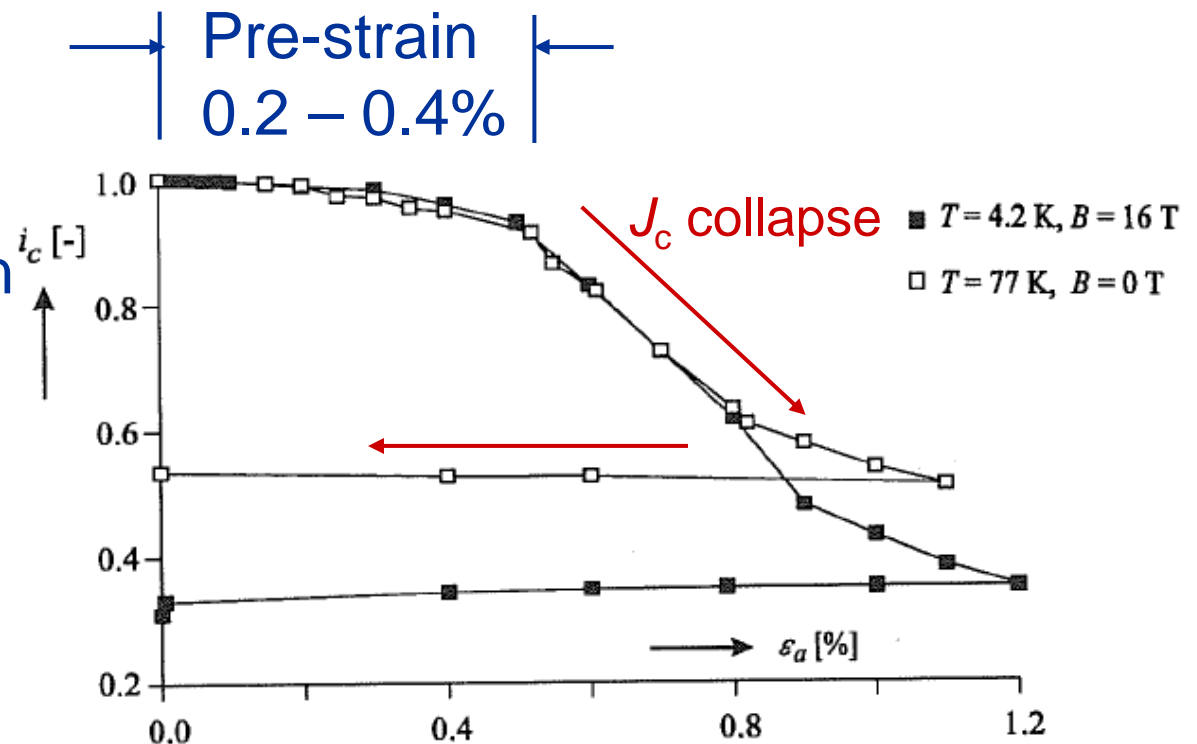
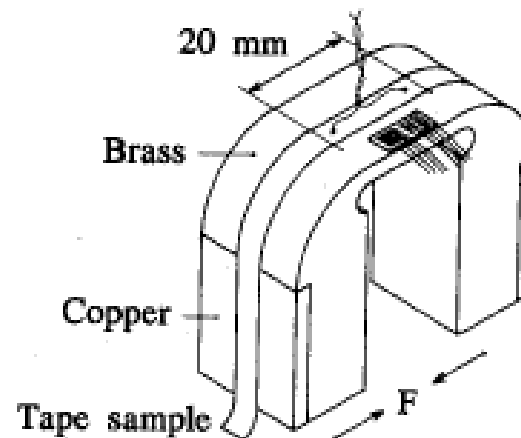


Figure 6.7: A comparison of the axial strain dependent critical current at two different conditions,  $n$  on the A-19 sample (Critical-current criterion:  $E_c = 10^{-3} \text{ V/m}$ ).

➔ Ten Haken, PhD Thesis, 1994

# Compressive: U-shaped bending springs



➡ Ten Haken, TAS, 1993



# Generalized axial behavior



## 3 regions

- I and III
  - ➔  $J_c$  collapses
  - ➔ Significant cracks
- II
  - ➔ Quasi constant
    - (Still irreversible)
    - Quasi-elastic behavior
    - Small cracks?
  - ➔ Length corresponds to pre-strain

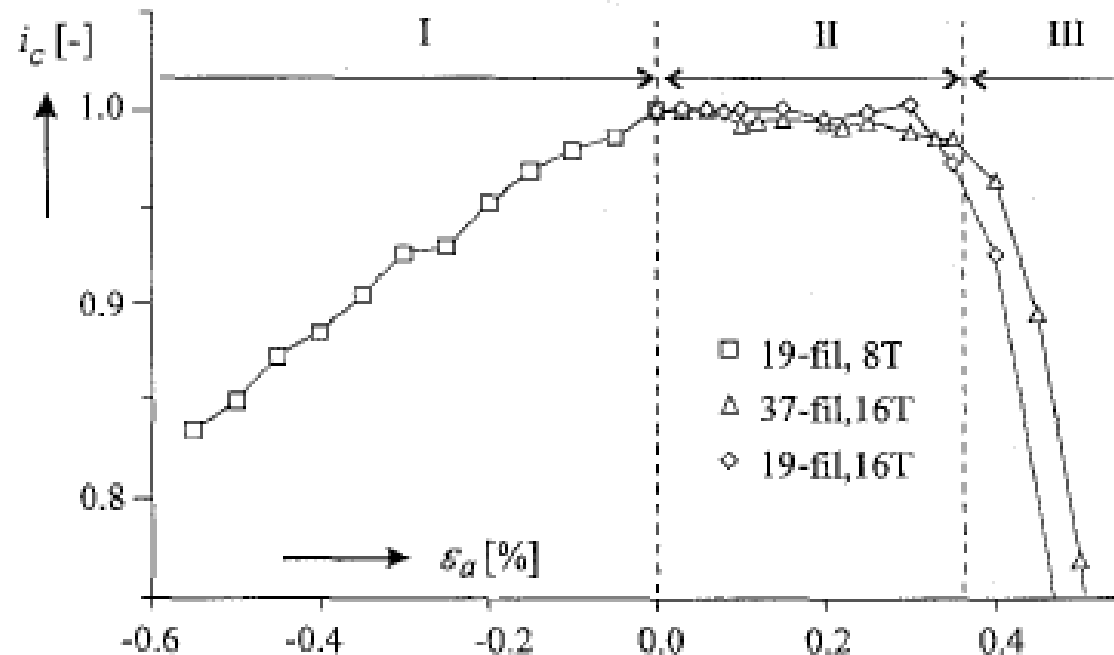


Fig. 1. The normalised critical current as a function of the axial strain. Measured on different samples for compressive and tensile strains (measured at 4.2 K and 8 or 16 T).

➔ Ten Haken, ToM, 1996

# Generalized axial behavior: A model

## Model...

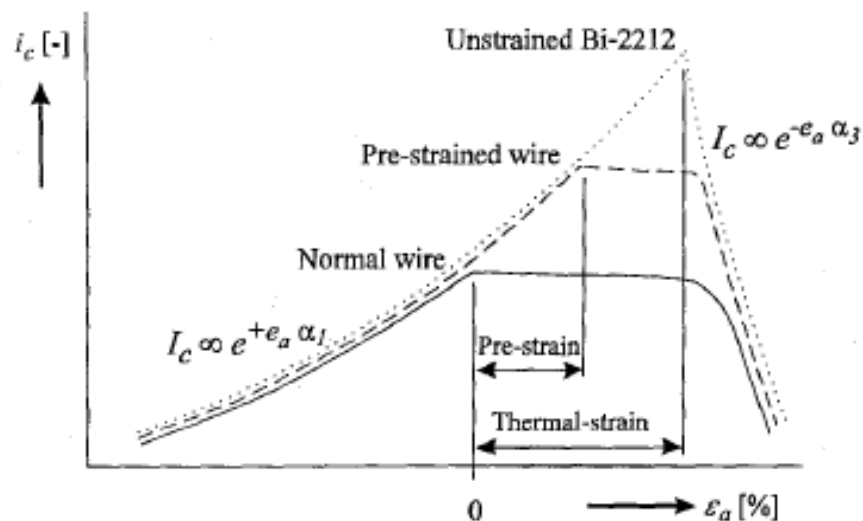
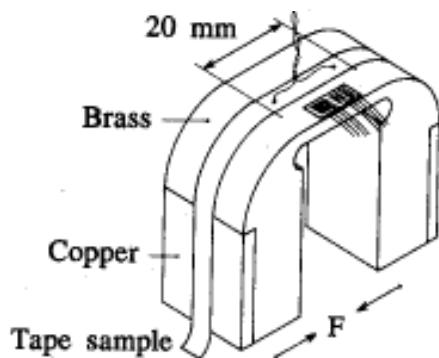


Fig. 2. The proposed description for the  $I_c(\epsilon_a)$  dependence of Bi-2212.



## ...and measurement

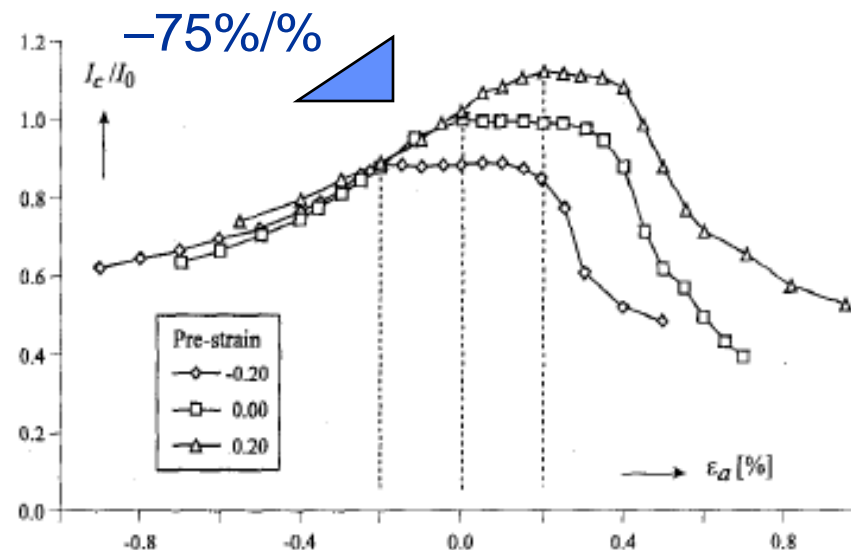


Fig. 3. The normalised critical current as a function of the axial strain measured on three pairs of pre-strained samples (measured at 4.2 K and 16 T).

► Ten Haken, ToM, 1996

- All axial compressive strain irreversibly reduces  $J_c$

# Model and irreversibility



## Repetitive 'low' strain variations

- All strain irreversible

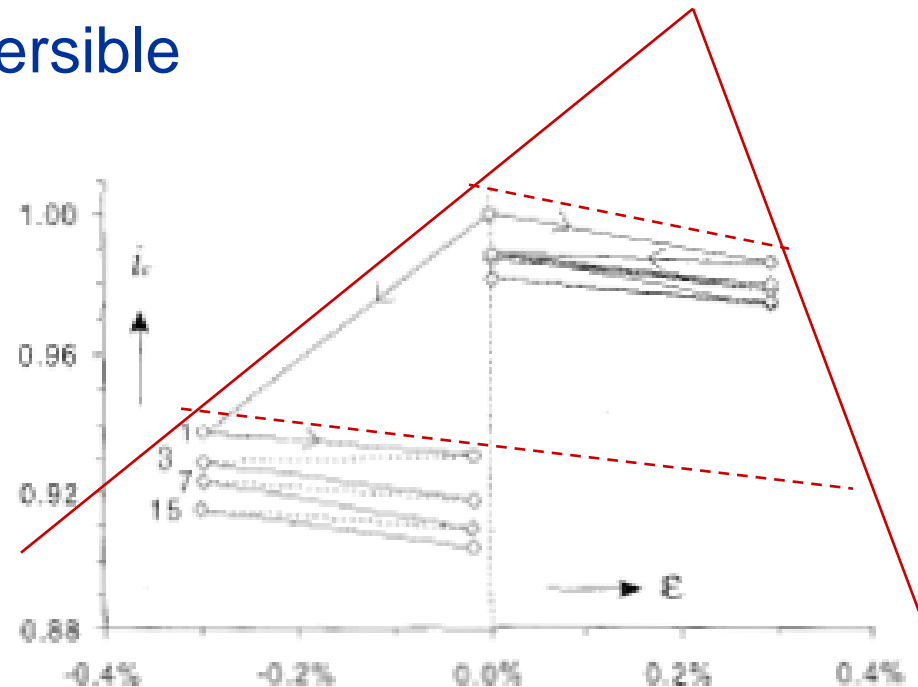


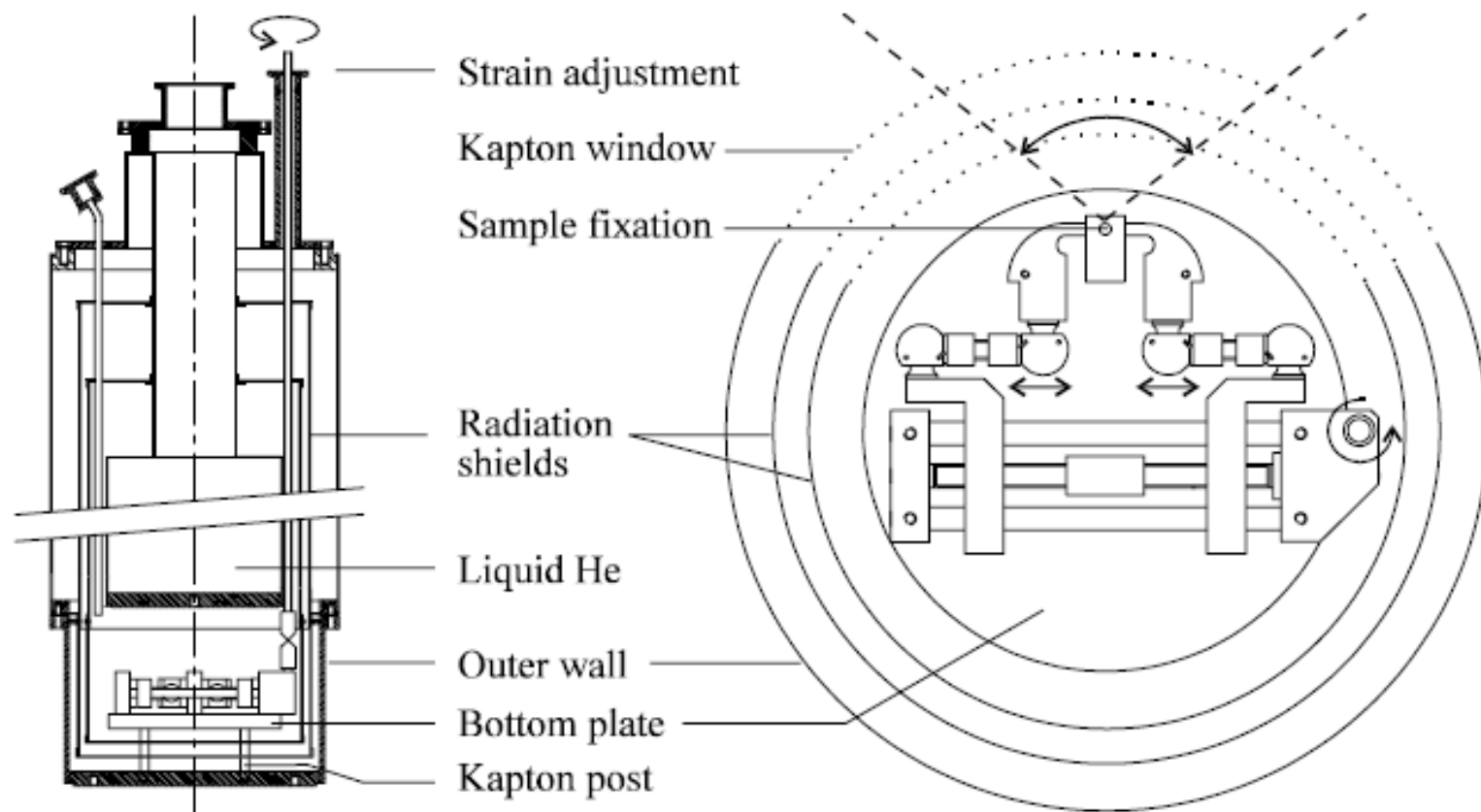
Fig. 5. The  $I_c$  versus strain in two samples of conductor A. First a cyclic deformation between 0 and 0.28% axial strain and then between 0 and -0.28% strain. The solid and dotted line follows the measuring sequence. The solid lines indicate two sequential  $I_c$  measurements and a dotted line is used when one or more strain cycles are skipped.

- Ten Haken, TAS, 1997

# Crack formation?



## Strain and X-ray diffraction



➡ Ten Haken, ACE, 1997

# Microscopic strain analysis with X-rays



## Apply external axial strain

- Shift in  $2\Theta$  for 0020 peak
  - Strain in c direction
  - $\epsilon_y = \nu_y \epsilon_z$

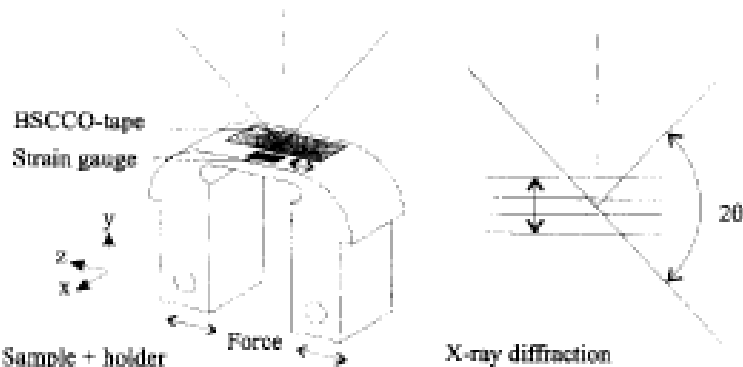
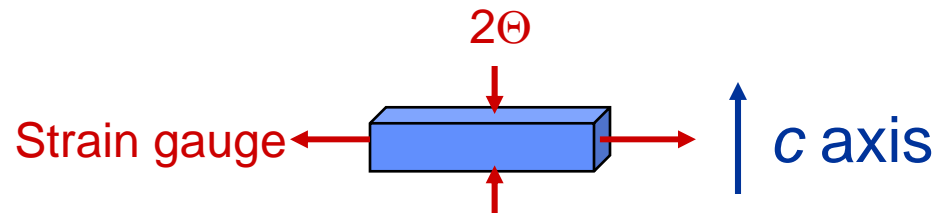


Fig. 1. Bi-2212 sample on the brass sample holder for the X-ray diffraction experiment.

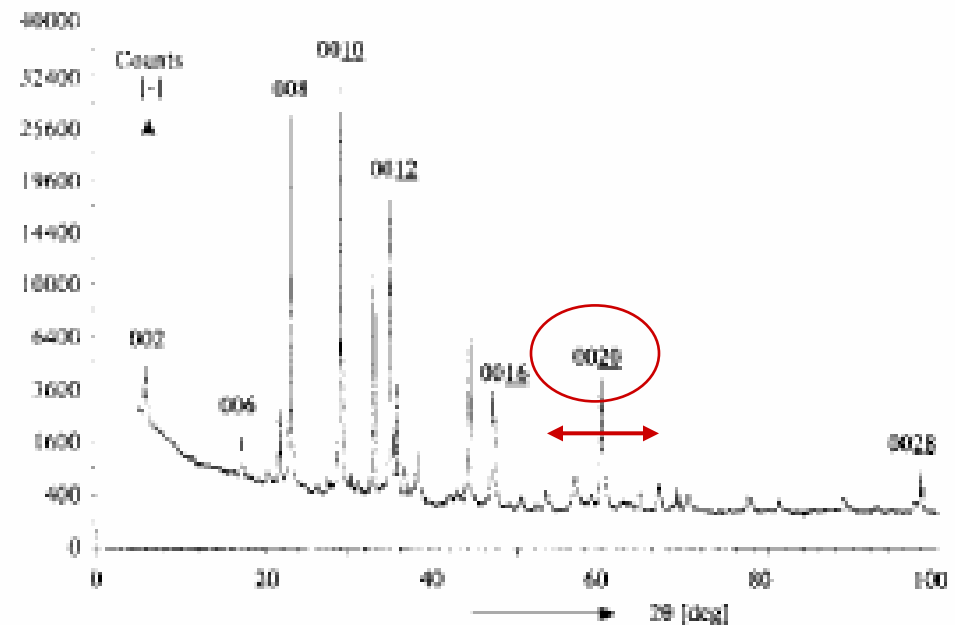


Fig. 2. The diffraction pattern with Cu-K $\alpha$  radiation on polycrystalline Bi-2212 at 300 K, on a non-deformed sample holder.

➤ Ten Haken, PhysC, 1996

# Shift 0020 position versus tensile strain



## Strain behavior

- c-axis compression with axial tensile strain
  - ➔ Elastic up to +0.2% axial
  - ➔ Cracks above +0.2% axial

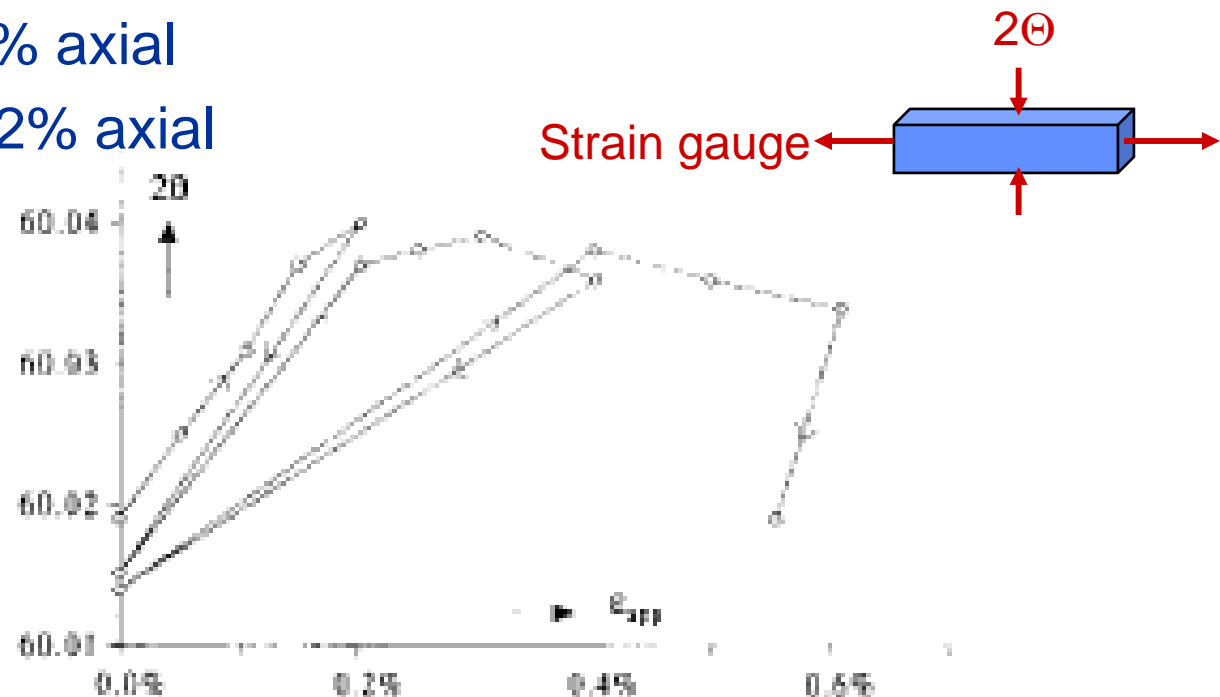


Fig. 3. The position of the diffraction peak of the 0020 reflection as a function of the applied axial strain as measured with the strain gauge at 300 K.

➔ Ten Haken, PhysC, 1996

# c-axis deformation and $J_c(\epsilon_{\text{axial}})$



## At $J_c(\epsilon_{\text{axial}})$ plateau

- c-axis deformation proportional to  $\epsilon_{\text{axial}}$
- Elastic behavior

## Outside $J_c(\epsilon_{\text{axial}})$ plateau

- c-axis is constant
- Elastic behavior disappears
- Cracks formation

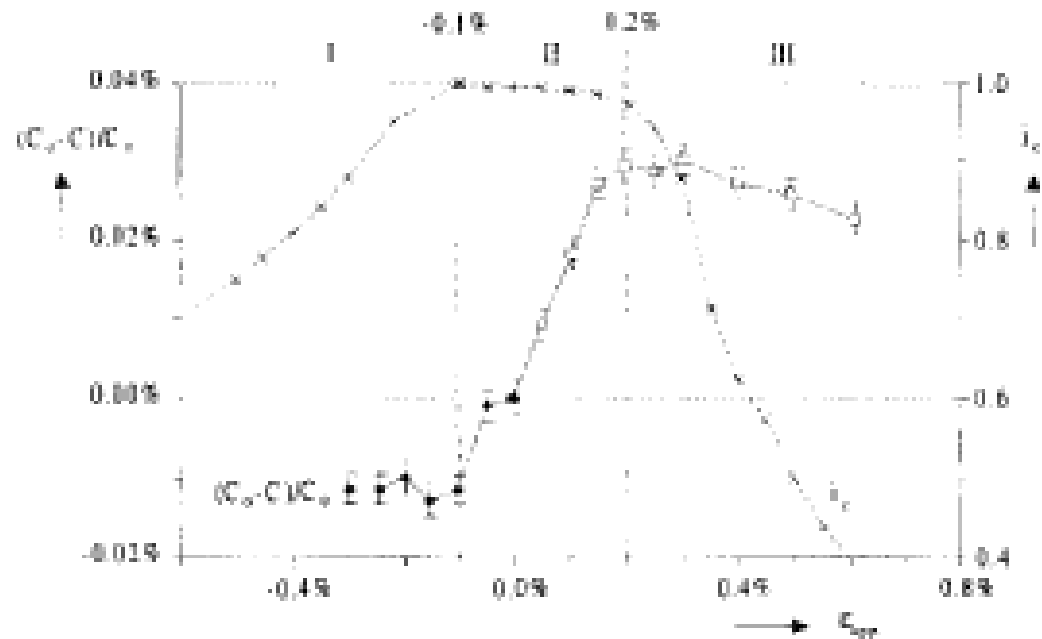
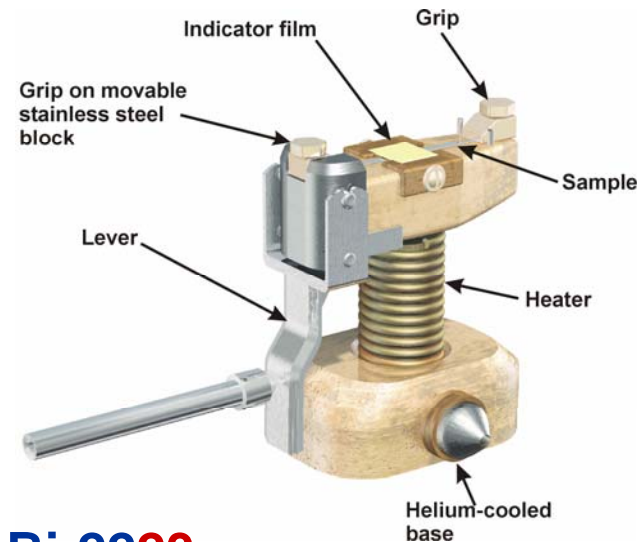
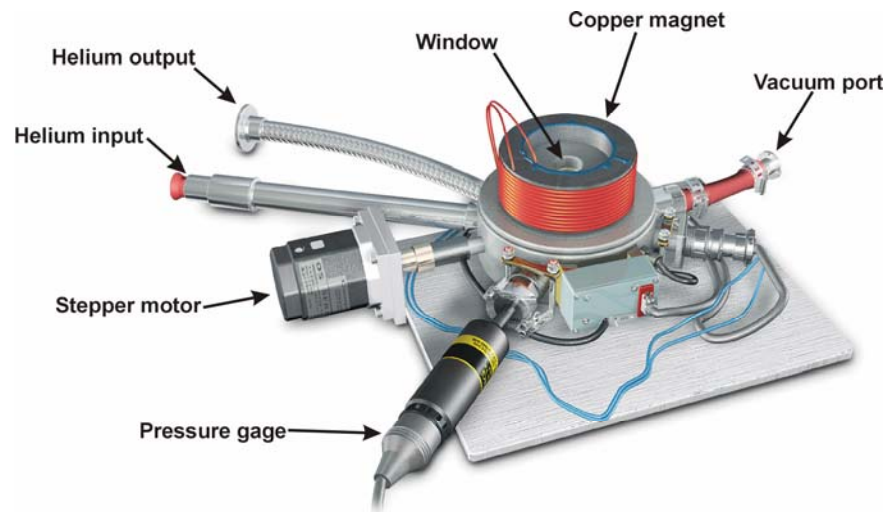


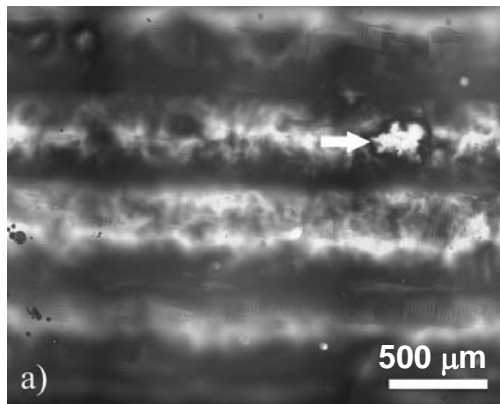
Fig. 4. The deformation of the *c*-axis as a function of the applied strain at 300 K, compared with the normalised  $J_c$  measured at 77 K on a deformed Bi-2212 mono-core wire [4].

► Ten Haken, PhysC, 1996

# Cracks: MOI on strained Bi-2212

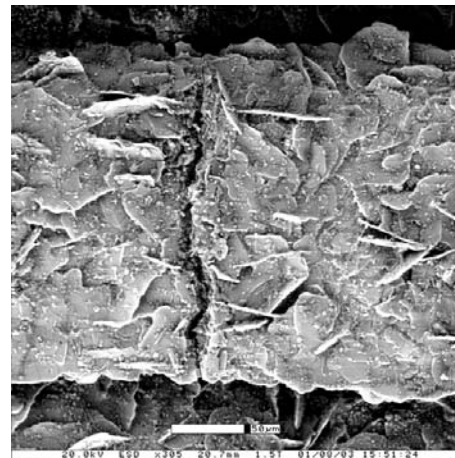


## Unstrained Bi-2212

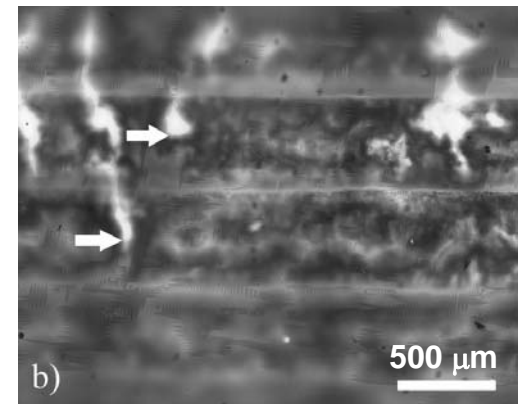


Filament  
Filament + pinhole  
Filament  
Filament

## Strained Bi-2212



## Strained Bi-2212



D.C. van der Laan – Ph.D. thesis, U. Twente 2004 (see Schwartz talk)

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# Crack formation confirmed with MOI



## Axial strain results: Crack formation from MOI and $J_c(\epsilon)$

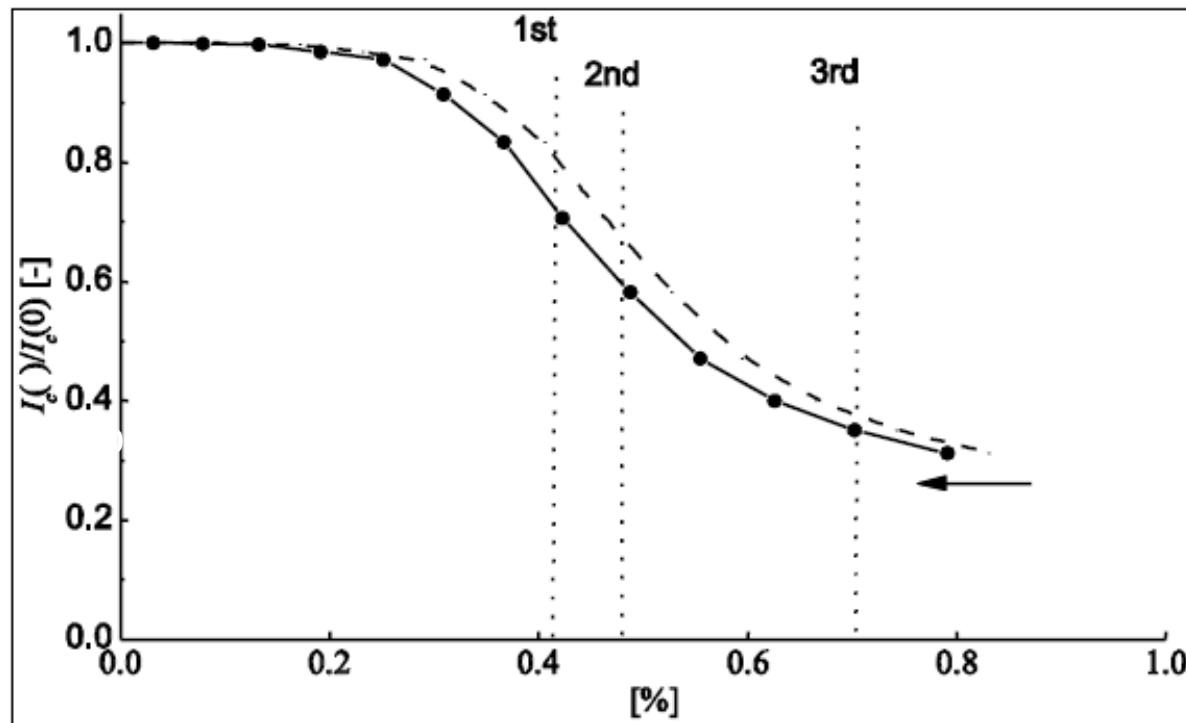


Figure 3.25. Normalized critical current vs. strain of Bi-2212 tape B-3 at 4.2 K. Cracks appear at applied strain of 0.41 % (1<sup>st</sup>), 0.48 % (2<sup>nd</sup>) and 0.70 % (3<sup>rd</sup>). The arrow shows the direction in which the curve shifts when correcting for the difference in pre-compression.

D.C. van der Laan – Ph.D. thesis, University of Twente 2004

# Transverse pressure on Bi-2212 tapes



From the 'House of Horrors'...

→ Very discouraging!

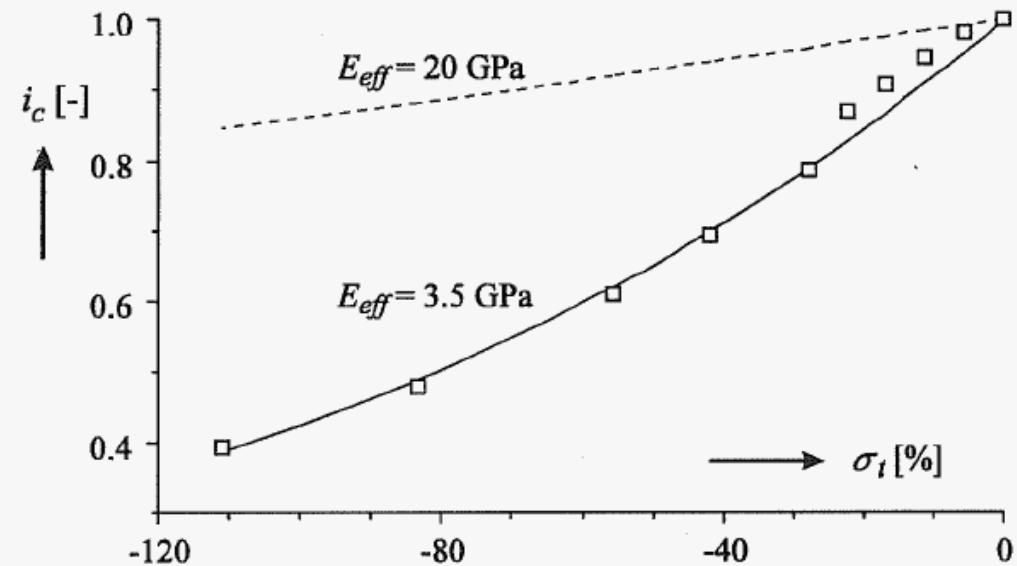
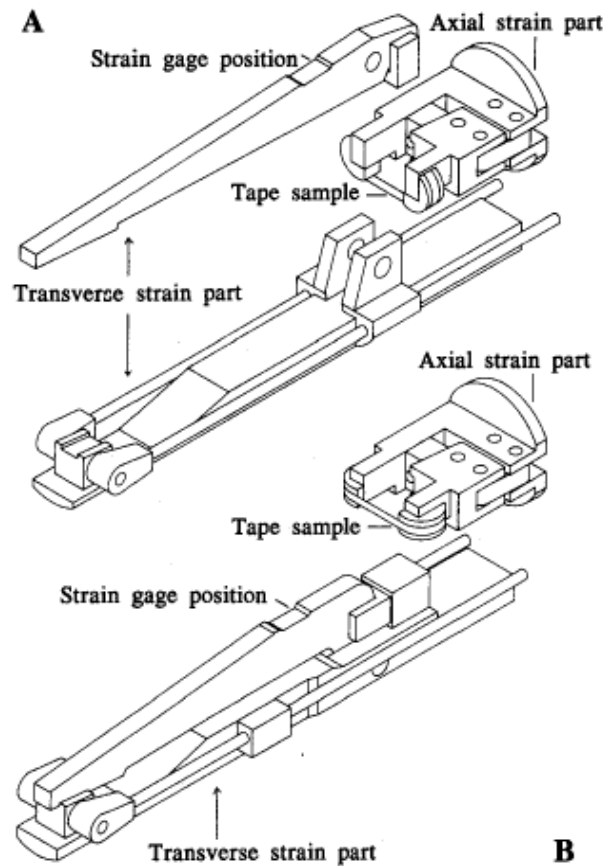


Figure 6.16: The normalised critical-current reduction of the Bi-2212 tape conductor (T-19) subjected to a transversal pressure, measured on the  $F_t // B$  transverse press. The measured  $I_c(\sigma_t)$  is compared with two lines representing the calculated  $I_c$  versus pressure dependence for two different Young's moduli ( $E_{eff} = 20$  and  $3.5 \text{ GPa}$ ).

→ Ten Haken, TAS, 1993; PhD thesis, 1994

# Transverse pressure on Bi-2212 cables



## Better than tapes...

- ...but insufficient?
- Limited to 60 MPa broad face load?

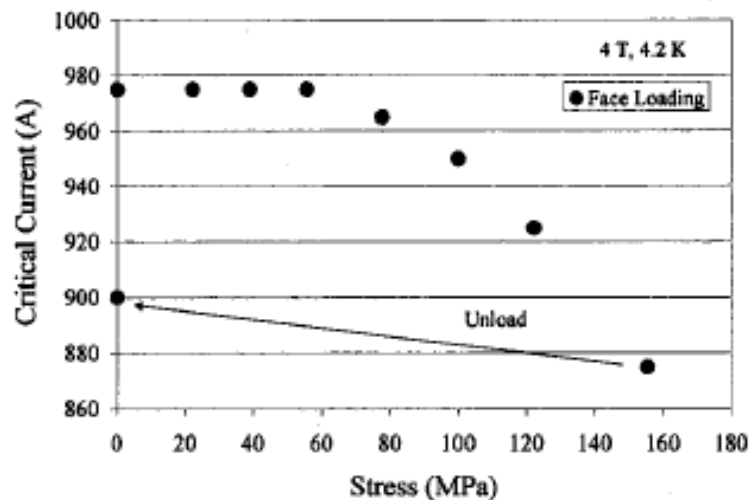


Fig. 3. Variation of the critical current (4 T, 4 K) with stress for a cable loaded on the broad face of the cable.

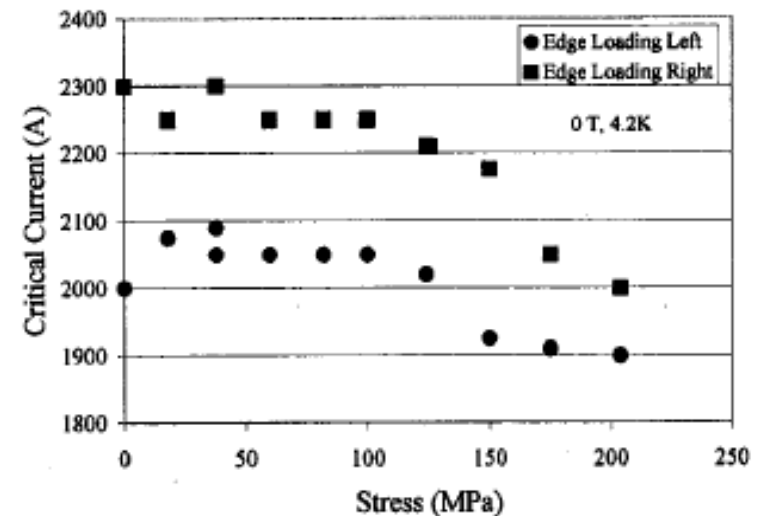


Fig. 4. Variation of the critical current (self-field, 4 K) with stress for a cable loaded on the edge of the cable.

➡ Dietderich, TAS, 2001

# Summary



- All strain causes an irreversible reduction of  $J_c$ 
  - ➔ Avoid it! (e.g. match thermal contractions)
- Irreversibility is a result of crack formation
  - ➔ Confirmed with X-ray diffraction
  - ➔ Confirmed with MOI
- No contradictive results found to 1996 model
  - Plateau length grows with pre-strain
  - Apparent larger 'strain margin'
    - ➔ At the cost of irrecoverable  $J_c$  reduction
- Transverse pressure effects cables better than on tapes
  - ➔ Similar as for  $Nb_3Sn$ 
    - But limits appear far from  $Nb_3Sn$ 's 200 MPa
  - ➔ Conductor reinforcement / stress relieve required